



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Assignee: KLA-TENCOR TECHNOLOGIES CORPORATION
Title: OVERLAY ERROR DETECTION
Serial No.: 09/697,025 Filing Date: October 26, 2000
Examiner: Unknown Group Art Unit: 2623
Docket No.: M-10697 US

San Jose, California
April 4 2001

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants wish to call the enclosed documents to the attention of the Examiner. A PTO form 1449 listing these documents is enclosed.

Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to the Commissioner for Patents, Washington, D.C. 20231, on APR 4, 2001.

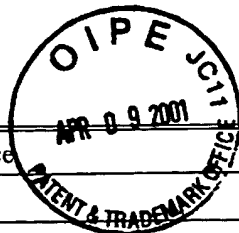
Tammy L. Kaplan 4/4/01
Date of Signature

Respectfully submitted,

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U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					M-10697 US		09/697,025	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicant(s)			
(Use several sheets if necessary)					MEHRDAD NIKOONAHAD ET AL.			
					Filing Date		Group	
					October 26, 2000		2623	

U.S. Patent Documents							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,023,338	2/8/2000	Bareket	356	401	7/12/96
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents							Translation	
Document	Date	Country	Class	Subclass	Yes	No		
AL								
AM								
AN								
AO								
AP								

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
AQ	"Microinterferometre differentiel a ondes polarises," G. Nomarski, <i>J. Phys Radium</i> 16, (S-13S (1955))	
AR	"Lithography Process Control," H. Levinson, <i>SPIE press</i> , Vol. TT28, Bellingham, Washington, 1999	
AS		

Examiner	Date Considered
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***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.